

## MOS FIELD EFFECT TRANSISTOR NP34N03HLD, NP34N03ILD

### SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

#### DESCRIPTION

This product is N-Channel MOS Field Effect Transistor designed for high current switching applications.

#### FEATURES

- Channel Temperature 175 Degree Rated
- Super Low On-state Resistance  
 $R_{DS(on)1} = 12.5 \text{ m}\Omega$  (MAX.) ( $V_{GS} = 10 \text{ V}$ ,  $I_D = 17 \text{ A}$ )  
 $R_{DS(on)2} = 16 \text{ m}\Omega$  (MAX.) ( $V_{GS} = 5 \text{ V}$ ,  $I_D = 17 \text{ A}$ )
- Low  $C_{iss}$  :  $C_{iss} = 2290 \text{ pF}$  (TYP.)
- Built-in Gate Protection Diode

#### ORDERING INFORMATION

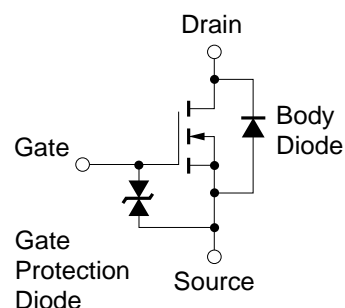
PART NUMBER	PACKAGE
NP34N03HLD	TO-251
NP34N03ILD	TO-252

#### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ )

Drain to Source Voltage	$V_{DSS}$	30	V
Gate to Source Voltage	$V_{GSS}$	$\pm 20$	V
Drain Current (DC)	$I_{D(DC)}$	$\pm 34$	A
Drain Current (Pulse) <sup>Note</sup>	$I_{D(pulse)}$	$\pm 120$	A
Total Power Dissipation ( $T_A = 25^\circ\text{C}$ )	$P_T$	1.2	W
Total Power Dissipation ( $T_{ch} = 25^\circ\text{C}$ )	$P_T$	51	W
Channel Temperature	$T_{ch}$	175	$^\circ\text{C}$
Storage Temperature	$T_{stg}$	$-55 \text{ to } +175$	$^\circ\text{C}$

**Note.**  $PW \leq 10 \mu\text{s}$ , Duty cycle  $\leq 1\%$

#### EQUIVALENT CIRCUIT



#### THERMAL RESISTANCE

Channel to Case	$R_{th(ch-c)}$	2.94	$^\circ\text{C/W}$
Channel to Ambient	$R_{th(ch-a)}$	83.3	$^\circ\text{C/W}$

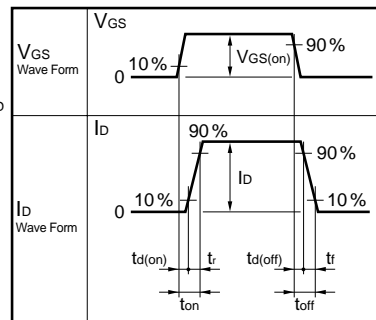
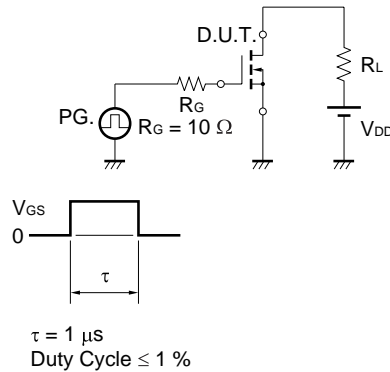
**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

The information contained in this document is being issued in advance of the production cycle for the device. The parameters for the device may change before final production or NEC Corporation, at its own discretion, may withdraw the device prior to its production.

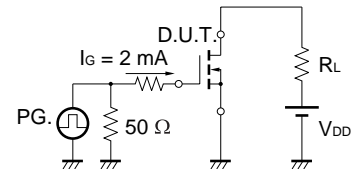
**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C)**

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	R <sub>DS(on)1</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 17 A		9.8	12.5	mΩ
	R <sub>DS(on)2</sub>	V <sub>GS</sub> = 5 V, I <sub>D</sub> = 17 A		12	16	mΩ
	R <sub>DS(on)3</sub>	V <sub>GS</sub> = 4 V, I <sub>D</sub> = 17 A		15	19	mΩ
Gate to Source Cutoff Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.0	1.5	2.0	V
Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 17 A	15			S
Drain Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V			10	μA
Gate to Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μA
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		2290	3440	pF
Output Capacitance	C <sub>oss</sub>			940	1410	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			440	690	pF
Turn-on Delay Time	t <sub>d(on)</sub>	I <sub>D</sub> = 17 A, V <sub>GS(on)</sub> = 10 V, V <sub>DD</sub> = 15 V, R <sub>G</sub> = 10 Ω		40	90	ns
Rise Time	t <sub>r</sub>			427	1070	ns
Turn-off Delay Time	t <sub>d(off)</sub>			174	350	ns
Fall Time	t <sub>f</sub>			226	570	ns
Total Gate Charge	Q <sub>G</sub>	I <sub>D</sub> = 34 A, V <sub>DD</sub> = 24 V, V <sub>GS</sub> = 10 V		45	68	nC
Gate to Source Charge	Q <sub>GS</sub>			6.3		nC
Gate to Drain Charge	Q <sub>GD</sub>			16		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 34 A, V <sub>GS</sub> = 0 V		1.0		V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 34 A, V <sub>GS</sub> = 0 V, di/dt = 100 A/μs		49		ns
Reverse Recovery Charge	Q <sub>rr</sub>			50		nC

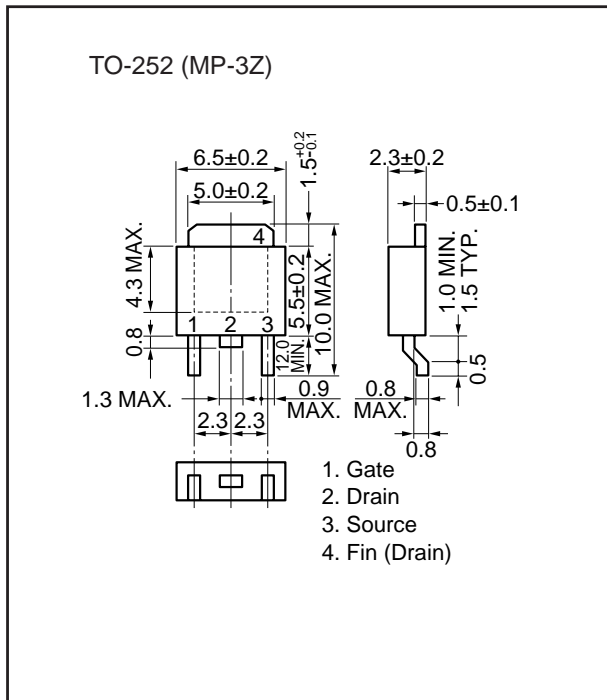
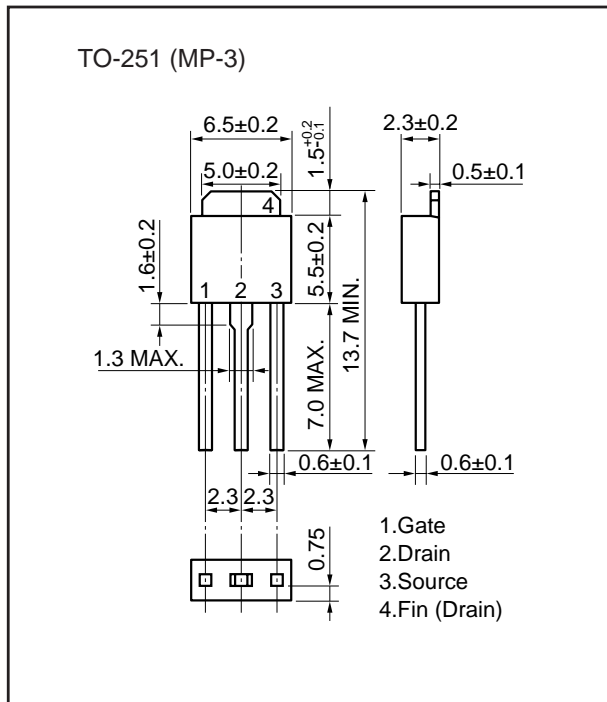
**TEST CIRCUIT 1 SWITCHING TIME**



**TEST CIRCUIT 2 GATE CHARGE**



PACKAGE DRAWINGS (Unit : mm)



No part of this document may be copied or reproduced in any form or by any means without the prior written consent of NEC Corporation. NEC Corporation assumes no responsibility for any errors which may appear in this document.

NEC Corporation does not assume any liability for infringement of patents, copyrights or other intellectual property rights of third parties by or arising from use of a device described herein or any other liability arising from use of such device. No license, either express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of NEC Corporation or others.

While NEC Corporation has been making continuous effort to enhance the reliability of its semiconductor devices, the possibility of defects cannot be eliminated entirely. To minimize risks of damage or injury to persons or property arising from a defect in an NEC semiconductor device, customers must incorporate sufficient safety measures in its design, such as redundancy, fire-containment, and anti-failure features.

NEC devices are classified into the following three quality grades:

"Standard", "Special", and "Specific". The Specific quality grade applies only to devices developed based on a customer designated "quality assurance program" for a specific application. The recommended applications of a device depend on its quality grade, as indicated below. Customers must check the quality grade of each device before using it in a particular application.

Standard: Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots

Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)

Specific: Aircrafts, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems or medical equipment for life support, etc.

The quality grade of NEC devices is "Standard" unless otherwise specified in NEC's Data Sheets or Data Books. If customers intend to use NEC devices for applications other than those specified for Standard quality grade, they should contact an NEC sales representative in advance.

Anti-radioactive design is not implemented in this product.